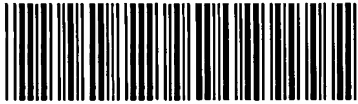


**Search Notes**

Application/Control No.

10/710,288

Examiner

Cong-Lac Huynh

Applicant(s)/Patent under  
Reexamination

BEYER ET AL.

Art Unit

2178

**SEARCHED**

Class	Subclass	Date	Examiner
715	500	7/3/2007	CLH
	513	7/3/2007	CLH
	514	7/3/2007	CLH
707	1, 3	7/3/2007	CLH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	7/3/2007	CLH
ACM	7/5/2007	CLH